

International Standard

ISO 5577

Non-destructive testing — Ultrasonic testing — Vocabulary

Essais non destructifs — Contrôle par ultrasons — Vocabulaire

Third edition 2025-09

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Contents			Page
Fore	word		iv
1	Scop	ne	
2	Norn	native references	
3	Tern	ns and definitions	
4	Tern 4.1 4.2 4.3	ns related to frequencies, waves and pulses Frequencies Waves and pulses Types of ultrasonic waves	3
5	Tern 5.1 5.2 5.3 5.4	ns related to sound Sound generation and reception Sound propagation Loss of sound pressure Ultrasonic waves at interfaces	6 7 10
6	Tern 6.1 6.2 6.3 6.4	Instrument Probes Combined test equipment Instrument setting, reference blocks and test blocks	14
7	Tern 7.1 7.2 7.3 7.4 7.5 7.6 7.7	Testing techniques Test object Coupling Reflectors Signals and indications Presentations Location Evaluation of indications	
Bibl Inde	iograph ps://stai	iy <u>ISO 5577;2025</u> ndards.iteh.ai/catalog/standards/iso/4fb9f233-841f-44d3-80ac-862d5d43b843	

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Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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This document was prepared by Technical Committee ISO/TC 135, Non-destructive testing, Subcommittee SC 3, Ultrasonic testing, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 138, Non-destructive testing, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

This third edition cancels and replaces the second edition (ISO 5577:2017), which has been technically revised. ISO 5577:2025

The main changes are as follows:

- terms pulse overshoot, main lobe, main beam, side lobe, diffraction, contact surface, echo amplitude, signal amplitude, and full screen height have been added;
- the term "plate wave" was replaced by "Lamb wave";
- some definitions and figures have been revised.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Non-destructive testing — Ultrasonic testing — Vocabulary

Scope 1

This document defines the terms used in ultrasonic non-destructive testing and forms a common basis for standards and general use.

This document does not cover specific terms used in ultrasonic testing with arrays.

NOTE Terms used in ultrasonic testing with arrays are defined in ISO 23243.

2 **Normative references**

There are no normative references in this document.

Terms and definitions

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at https://www.iso.org/obp
- IEC Electropedia: available at https://www.electropedia.org/

Terms related to frequencies, waves and pulses

Frequencies 4.1

T. III ps://standards.iteh.ai/catalog/standards/iso/4fb9f233-841f-44d3-80ac-862d5d43b843/iso-5577-2025 frequency

number of cycles per second

Note 1 to entry: Expressed in Hertz (Hz).

4.1.2

nominal frequency

probe frequency

frequency (4.1.1) of the probe (6.2.1) as stated by the manufacturer

4.1.3

test frequency

effective ultrasonic frequency of a system used to test a material or object

4.1.4

amplitude spectrum

distribution of *amplitude* (4.2.2) in relation to *frequency* (4.1.1)

Note 1 to entry: See Figure 1.

4.1.5

centre frequency

arithmetic mean of the upper and lower *cut-off frequencies* (4.1.7)

Note 1 to entry: See Figure 1.

4.1.6

peak frequency

frequency (4.1.1) at which the maximum amplitude is observed

Note 1 to entry: See Figure 1.

4.1.7

cut-off frequency

frequency (4.1.1) at which the amplitude (4.2.2) of the transmitted signal has dropped by a specified amount from the amplitude at peak frequency (4.1.6)

Note 1 to entry: See Figure 1.

Note 2 to entry: The transmitted signal can drop e.g. by 3 dB.

4.1.8

bandwidth

width of the amplitude spectrum (4.1.4) between the upper and lower cut-off frequency (4.1.7)

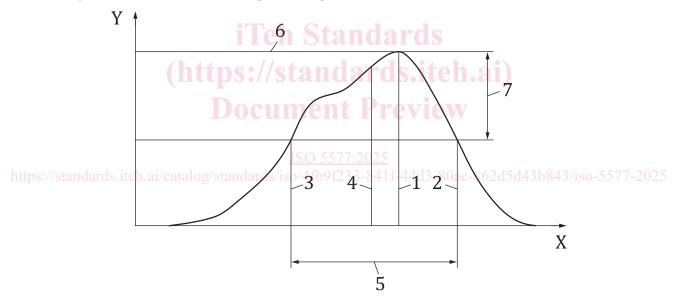
Note 1 to entry: See Figure 1.

4.1.9

relative bandwidth

ratio of the bandwidth (4.1.8) to the centre frequency (4.1.5)

Note 1 to entry: The relative bandwidth is expressed in per cent.



Key X frequency amplitude Y 1 peak frequency 2 upper cut-off frequency 3 lower cut-off frequency 4 centre frequency 5 bandwidth at specified amplitude drop 6 peak amplitude 7 specified amplitude drop

Figure 1 — Amplitude spectrum and related terms

4.2 Waves and pulses

4.2.1

ultrasonic wave

any acoustic wave having a *frequency* (4.1.1) higher than the audible range of the human ear, generally taken as higher than 20 kHz

4.2.2

amplitude

absolute or relative measure of a sound wave's momentary magnitude

Note 1 to entry: The amplitude is not necessarily the maximum value, see echo amplitude (7.5.6).

4.2.3

phase

momentary condition of a vibration expressed as an arc measurement or an angle

4.2.4

wavelength

distance along the propagating direction between consecutive corresponding points of the same *phase* (4.2.3)

Note 1 to entry: See Figure 3.

4.2.5

wavefront

continuous surface joining all the most forward points of an *ultrasonic wave* (4.2.1) that have the same *phase* (4.2.3)

4.2.6

time of flight

TOF

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time it takes an ultrasonic pulse to travel from the transmitting transducer through the *test object* (7.2.1) to the receiving transducer, including the *delay path(s)* (6.2.9)

4.2.7

pulse

ISO 5577:2024

electrical or ultrasonic signal of short duration 46696233-8416-4443-80ac-862d5d43b843/iso-5577-2025

4.2.8

pulse amplitude

maximum amplitude of a pulse (4.2.7)

Note 1 to entry: For rectified pulses (e.g. in an A-scan presentation), baseline-to-peak.

Note 2 to entry: For unrectified pulses, peak-to-peak.

4.2.9

pulse rise time

time taken for the amplitude of a pulse (4.2.7) to change from a specified lower level to a specified upper level

4.2.10

pulse duration

time interval between the leading and trailing edges of a *pulse* (4.2.7) measured at a specified level below the peak amplitude

4.2.11

pulse shape

diagramatic representation of the *amplitude* (4.2.2) of a *pulse* (4.2.7) as a function of time

4.2.12

pulse envelope

contour of a pulse shape (4.2.11) including all the peaks in terms of amplitude (4.2.2) and time